



Digitizer ASIC Options for LAPPD Applications

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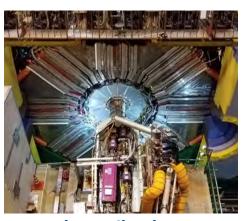
WAVEFORM DIGITIZER SoCs FOR PRECISE TIME OF FLIGHT ESTIMATION











1. Front-end Chips:

- Event based digitizer+DSP
- 4-32 channel scope on chip
- 1-15 Gsa/s, 12 bit res.
- Low SWaP-C
- User friendly: FW/SW tools

2. Integration:

- SiPM
- PMT
- LAPPD
- Detector arrays

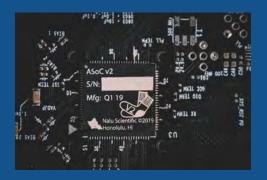
3a. Main application:

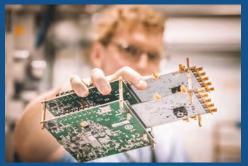
- NP/HEP experiments
- Astro particle physics

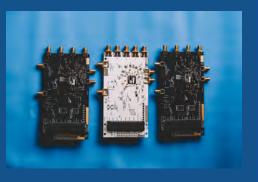
3b. Other applications:

- Beam Diagnostics
- Plasma/fusion diagnostics
- Lidar
- PET imaging

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ABOUT NALU SCIENTIFIC

Fast Growing Startup in Honolulu, Hawai'i

Located at the Manoa Innovation Center near U. of Hawaii 18 staff members-diverse background Access to advanced design tools Rapid prototyping and testing lab

Technical Expertise

IC design: Analog + digital System-on-Chip (SoC)

<u>Hardware design:</u> Complex multi-layer PCBs

<u>Firmware design:</u> FPGAs, CPUs

<u>Software design:</u> GUI, analysis, documentation

Scientific Expertise - NP/HEP subject matter experts

Physicists (3x) - Recent hire: Kevin Flood Electronics for large scientific instruments

Exclusive Distributor Agreement for North America

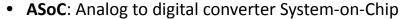
Sales of ASICs, eval boards Enhanced OEM opportunities





Current SoC-ASIC Projects

Project	Sampling Frequency (GHz)	Input BW (GHz)	Buffer Length (Samples)	Number of Channels	Timing Resolution (ps)	Available Date
ASoC	3-5	0.8	16k	4	35	Rev 3 avail
HDSoC	1-3	0.6	2k	64	80-120	Rev 1 avail
AARDVARC	8-14	2.5	32k	4	4	Rev 3 avail
AODS	1-2	1	8k	1-4	100-200	Rev 2 avail
UDC	10	1.8	2048	16	5-10	Rev 1 avail
STRAWZ	5	2	2k	64	10	TBD
HPSoC	8-10	2	2k	64	4	Dec'23



- HDSoC: SiPM specialized readout chip with bias and control
- AARDVARC: Variable rate readout chip for fast timing and low deadtime
- AODS: Low density digitizer with High Dynamic Range (HDR) option
- **STRAWZ:** Streaming Autonomous Waveform-digitizer with Zero-suppression
- **HPSoC:** High Pitch digitizer SoC: AC-LGADs specific readout

Work funded by DOE SBIRs. University of Hawaii as subcontractor.











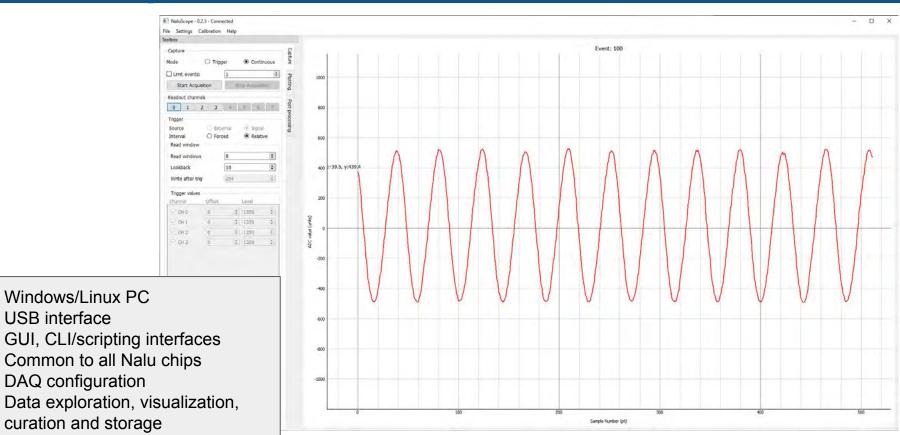


NaluScope Common Software and GUI

USB interface

Plug and play with eval cards





5



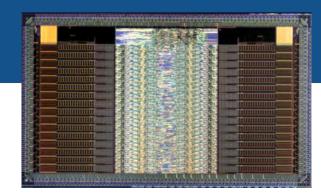
HDSoC VI DESIGN DETAILS

High density waveform digitizer with dead-timeless readout

- High Density: 64 channels
- Highly integrated, SiPM gain + bias
- Commercially available, low cost CMOS

Parameter	Spec		
Sampling Rate	1-2 GSa/s		
ABW	> 600MHz		
Depth	2k Sa		
Trigger Buffer	~3 us*		
Deadtime	0**		
Channels	64		
Supply/Range	2.5		
ADC bits	12		
Timing accuracy	80-120ps		
Technology	250 nm CMOS		
Power	TBD		

- On chip calibration
- Serial interface
- On chip feature extraction
- Virtually dead-timeless
- 32 ch proto chip fabricated
- Phase II SBIR in progress
- Chip under test
- Next steps: more testing, rev 2 fab



HDSoC v1 die shot

** Simulated Up to 240 KHz / ch with single serial link using on-chip self trigger and feature extraction. Up to 400 kHz / ch with additional serial links.

HDSoC - Current Status

• Fabrication:

- 32 channel prototype fabricated
- o 144 pin package purely for bring-up
- o Smaller QFN-100 available for integration

• Testing (functional):

- FMC eval card under testing
- o FW, SW developed
- Chip turns on, responds to commands
- Timing generators works well
- o All channels can digitize and readout
- o TIAs work, need more tests

• Next testing steps:

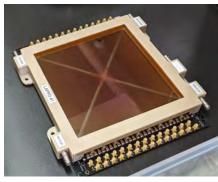
- Bias and readout SiPMs
- Characterize TIAs
- Test all digital functions and serial link
- Optimize chip biases
- Push for performance on data rate and quality



Integration efforts - HIPeR





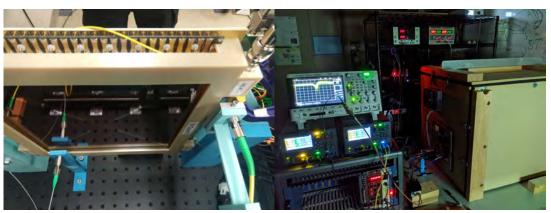


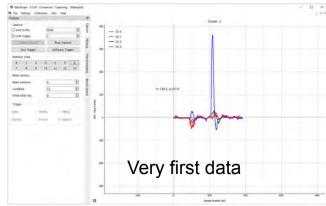


AARDVARC based readout

Incom's Gen 1 LAPPD

Integration and testing (UH)

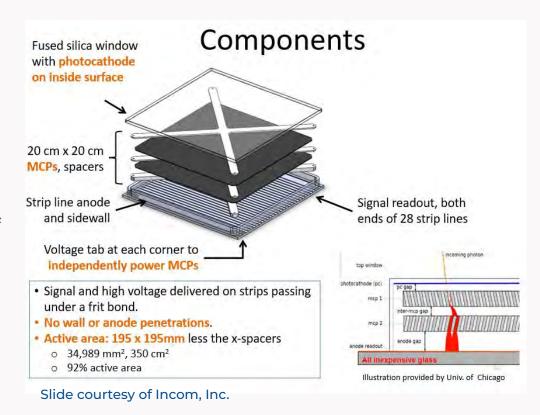




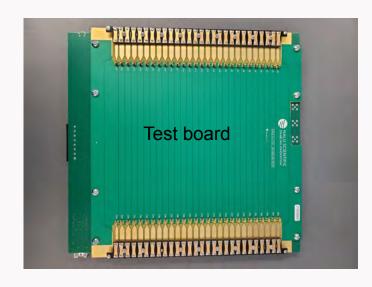
Nalu Scientific Phase I SBIR in collaboration with Incom and University of Hawaii.

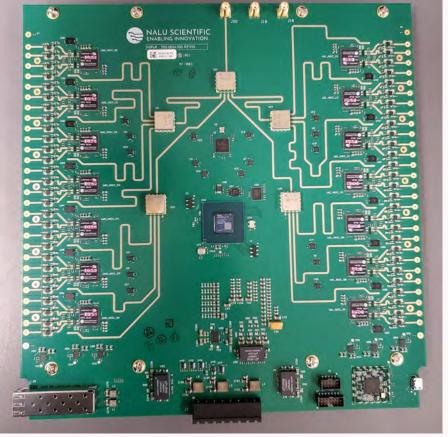
LAPPD Gen I

- Strip based readout:
 - MCP amplified p.e. are collected by metal strips
 - Strip identify "y" position of hit (sub-strip resolution possible via amplitude ratio of neighboring strips)
 - Arrival time difference on 2 sides of strip identify x position:
 - Requires very good timing resolution



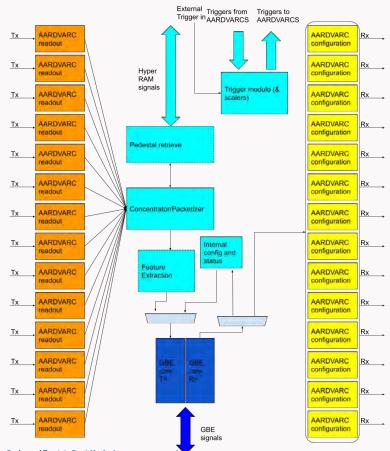
Fully Populated board





FW architecture

- Modular structure:
 - Easy to expand/add features
- Individual readout modules
- Individual configuration modules
- Concentrator kept simple in Phase I:
 - Pure packetization
 - Data pass through
 - Can add calibration/Feature extraction
- Triggering module separate:
 - External triggering:
 - Can still use individual channel triggers to limit data rate
 - Self triggering (streaming architecture)



LAPPD setup

Dedicated photodetector test setup:

- Large total area (61 x 61 x 76 cm 3), suitable for a full LAPPD tile
- Vibration isolated optical breadboard.
- Modular patchbay system
- Gasketing to seal against light leaks.
- 3D printed mounts for quick integration of LAPPD + readout electronics

• Scannable laser system:

- o 30.5 x 30.5 cm^2 scanning area.
- Fast PILAS laser.
- Fixed neutral density filters + variable optical attenuator
- Dual laser illumination positions

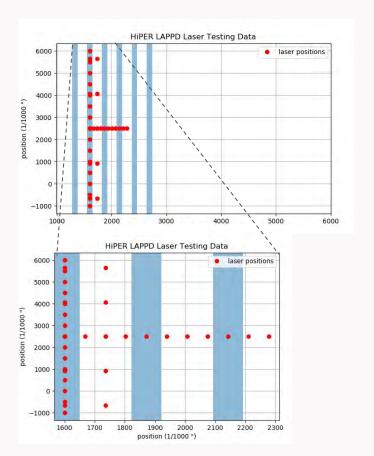
• Thermal management:

- o Thermoelectric cooling.
- o Temperature monitoring.
- o Temperature triggered power down safety interlocks.



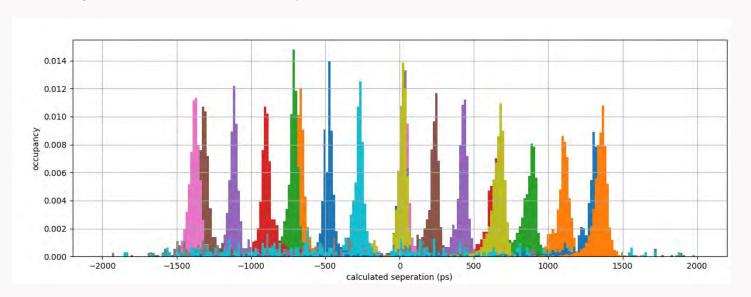
LAPPD scanning

- Acquisition has been repeated at various position for the incident laser pulse
- Used for probing the timing and positioning capability of the system
- In-between positions to estimate the position the y axis



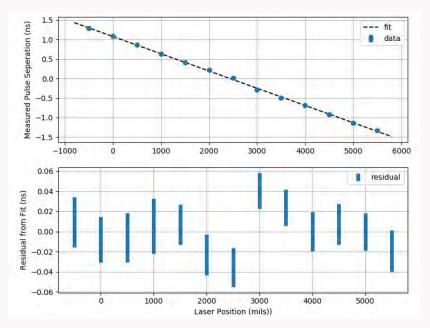
In strip position

- Scanning on a single strip
- Multiple acquisition in same position provide an histogram an estimate for x
- Histogram used to measure position and estimate error.



In strip position - results

- Mean from gaussian fit used for position expressed in time
- Standard deviation used for error bars
- Residuals from linear fit: typically 20 ps -> 2.3 mm
- More investigations into the outliers and effect of small pulses needed to confirm
- No chip timing cal yet



Summary

- NALU SCIENTIFIC ENABLING INNOVATION
 - **CAEN** Technologies Inc.

- Nalu Scientific Expertise:
 - FEEs for NP/HEP experiment readout
 - High integration (clock, memory, calibration)
 - Packaged chips and eval cards available
 - Additional testing under way including irradiation
 - Exclusive Distribution Agreement with CAEN
- Expertise:
 - NP/HEP electronics/FW development
 - Advanced ASIC/HW/FW/SW Design
 - Detector electronics design
- Funding:
 - SBIRs: covers costly chip development
 - Trade studies: initial assessment
 - <u>Custom design contracts</u>: Implementing new packaging and PCB designs
- Next steps OPEN FOR BUSINESS
 - Continue chip+PCB development
 - Continue engagement with experiments in order to tailor the designs to evolving experiment needs
 - New integration efforts under way, incl. NP ML/AI ASIC/FPGA SBIR proposal currently under review
 - Eval boards available for testing

